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Refined atomic coordinates for the sillimanite structure. By Slavomil Ďurovič, Refractories Research Institute, Bratislava, Czechoslovakia, and Štefánia Dávidová, Department of Mineralogy and Crystallography, Faculty of Natural Sciences, Komenský University, Bratislava, Czechoslovakia

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In the course of a comparison of the structure of mullite (Ďurovič, 1962a) with that of sillimanite (Ďurovič, 1962b), it was necessary to re-examine the sillimanite structure of Hey & Taylor (1930). One of the main results of the mullite structure analysis was the establishment of statistical occupation of the Al, Si* atomic positions (Fig. 1(a)). This statistical occupation was indicated by low peaks in the Fourier projection $\varrho(x,y)$, and confirmed during the refinement. The same result was obtained independently by Sadanaga, Tokonami & Takéuchi (1962). It was therefore desirable to determine whether the sillimanite structure showed a similar effect, especially as the experimental methods used by Hey & Taylor were insufficiently sensitive for this purpose.

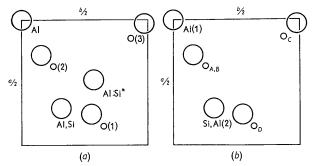


Fig. 1. Atomic positions in the mullite (a) and sillimanite (b) crystal structures.

For the re-examination crystals of the sillimanite variety xenolite (40.30% SiO₂, 59.60% Al₂O₃, 0.85% Fe₂O₃ and 0.07% TiO₂; ideal composition 62.93% Al₂O₃) were used. The measured density was 3.226 ± 2 g.cm.⁻³. The electron-density projection was calculated from 72 independent reflexions observed on Weissenberg photographs taken with Cu radiation. The structure was refined by repeated $F_o - F_c$ syntheses, the final R factor being 0.071 (0.068). The syntheses showed no Al, Si* maximum

of the type found in mullite (Fig. 1(b)). The final atomic coordinates are compared with those determined by Hey & Taylor in Table 1. The assignment of the z

Table 1. Refined atomic coordinates of sillimanite and those determined originally by Hey & Taylor

	This work			Hey & Taylor		
Atoms	x	\overline{y}	z	\overline{x}	\overline{y}	\overline{z}
Al(1)	0	0	0	0	0	0
Al(2)	0.352 ± 0.001	$0.158 \\ \pm 0.001$	$\frac{3}{4}$ ($\frac{1}{4}$)	0.36	0.15	34
Si	$0.352 \\ \pm 0.001$	$0.158 \\ \pm 0.001$	1 (1)	0.36	0.15	1
O_A	$0.139 \\ \pm 0.002$	$0.079 \\ \pm 0.002$	‡	0.15	0.07	4
O_B	$0.139 \\ \pm 0.002$	$0.079 \\ \pm 0.002$	34	0.15	0.07	3
O_C	$0.025 \\ \pm 0.002$	$0.490 \\ \pm 0.002$	34	0.03	0.47	ł
O_D	$0.374 \\ \pm 0.002$	$0.275 \\ \pm 0.002$	0	0.39	0.28	0

parameters was verified by comparison of observed and calculated values of F(h0l) and F(0kl).

No detailed analysis of the occupation of the tetrahedral positions was possible.

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The crystal structure of SnCl₂. A correction. By J. M. van den Berg, Laboratory of Inorganic Chemistry, University of Leiden. The Netherlands.

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The text of the paper by van den Berg, 1961, contains an error in the interatomic distances of the Sn atom at $z=\frac{1}{4}$ to the Cl atoms in the same plane. These distances should be 3.22, 2.66 and 3.30 Å. The distances in Fig. 1 are correct.

Reference

BERG, J. M. VAN DEN (1961). Acta Cryst. 14, 1002.